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	Sommario/riassunto	Featuring invaluable input from industry-leading companies and highly-regarded experts in the field, this first-of-its kind resource offers experienced engineers a comprehensive understanding of the advanced topics in RF, SiP (system-in-package), and SoC (system-on-a-chip) production testing that are critical to their work involving semiconductor devices. The book covers key measurement concepts for semiconductor device testing and assists engineers in explaining these concepts to management to aid in the reduction of project cost, time,

and resources. Based on real-world experience and packed with time-saving equations, this in-depth volume offers professionals practical information on essential topics that have never been presented in a single reference before.